Electronic Supplementary Material (ESI) for Journal of Materials Chemistry A. This journal is © The Royal Society of Chemistry 2022

Improved Synthesis and Transient Absorption Spectroscopy of $CuBiW_2O_8$ with Demonstration of Visible-Light-Driven Photocatalysis and Mechanistic Insights

Ceren Yilmaz Akkaya^a, James Dombrowski,^a Erika Colin-Ulloa,^b Lyubov V. Titova,^b Timothy J. Lawton,^c Todd Alexander,^c Eric Brack,^c Christopher Drew,^c Pratap M. Rao^a *

^oDepartment of Mechanical Engineering, Worcester Polytechnic Institute, Worcester, Massachusetts, 01609, USA ^bDepartment of Physics, Worcester Polytechnic Institute, Worcester, Massachusetts, 01609, USA ^cSoldier Protection Directorate, US Army Combat Capabilities Development Command Soldier Center, Natick, Massachusetts, 01760, USA *Corresponding Author: E-mail address: pmrao@wpi.edu (Pratap M. Rao)

Supporting Information

Table of Contents

Table	of Figures	.1				
1.	Synthesis Procedure and Optimization of the Synthesis to Obtain Cu ₂ WO ₄ as Precursor	.2				
1.1	Synthesis of CuWO₄	.2				
1.2	2 Synthesis of Cu ₂ WO ₄	.3				
2.	Optical and Photocatalytic Properties of CBTO	.7				
3.	Estimation of number of Cr(VI) ions to CBTO surface atom ratio11					
4.	References	12				

Table of Figures

Fig. S1 Raman spectrum (left) and powder XRD diagram (right) of CuWO ₄ (standard pattern (ICDD PDF 04-018-	
2380) is also included for comparison)	2
Fig. S2 XRD diagram of Cu_2WO_4 prepared by comproportionation of copper metal powder (5 μ m) and $CuWO_4$	
(standard pattern (ICDD PDF 00-041-0948) is also included for comparison)	3
Fig. S3 (a) CBTO powder collected by opening the copper box, inverting it, and tapping, (b) XRD patterns of the collected CBTO powder prepared by Cu ₂ WO ₄ based route at 800 °C for 4 h in Cu rich atmosphere by different scientists six months apart.	t 4
Fig. S4 Comparison of the XRD diagrams of CBTO prepared by annealing 4 times at 600 °C for 9 hours with intermittent ball milling after each annealing with a) Cu ₂ WO ₄ or b) Cu ₂ O as ternary and binary precursors in	
Cu rich atmosphere (\bigstar CBTO, \blacktriangle Bi ₂ WO ₆ , \blacktriangledown Bi ₂ W ₂ O ₉ , \bullet WO ₃)	4
Fig. S5 SEM images of CBTO prepared by Cu ₂ WO ₄ based route at 800 °C for 4 h in Cu rich atmosphere (a,b) as- synthesized and (c,d) after ball milling	5
Fig. S6 Atomic % data from various points on ball-milled CBTO obtained by SEM - energy dispersive X-ray spectroscopy (EDS)	6
Fig. S7 XRD diagrams of as-synthesized and ball-milled CBTO powders	7
Fig. S8 (a) UV-Vis spectrum of CBTO powder dispersed in water. (b) Valence and conduction band edges of CBTO ⁶	7
Fig. C0 $(r/1/1)$ abstaraduction with CDTO under overlation with 100 m/1/2m ² light 40 ml of E mg/1 $(r/1/1)$ colution	′
10 mM CA, pH=2 unless stated otherwise (a) influence of citric acid concentration, (b) influence of the	

- 1. Synthesis Procedure and Optimization of the Synthesis to Obtain Cu₂WO₄ as Precursor

1.1 Synthesis of CuWO₄

The CuWO₄ microcrystals were synthesized by following a reported procedure.¹ CuO (10 mmol) and WO₃ (10 mmol) were ground to a uniform powder by mortar and pestle before the mixture was transferred to an open-top high-alumina cup crucible and placed in a box oven under ambient atmosphere. The sample was heated to 800 °C (3 h ramp time) before being held isothermally for 12 hours and left to cool ambiently to ~20 °C. The ochre-colored homogeneous powder was collected and ground by mortar and pestle to a fine powder. The observed Raman-active modes and XRD peaks for the obtained product are in line with the published data indicating highly crystalline, pure, triclinic CuWO₄ (Fig. S1)².



Fig. S1 Raman spectrum (left) and powder XRD diagram (right) of CuWO₄ (standard pattern (ICDD PDF 04-018-2380) is also included for comparison)

1.2 Synthesis of Cu₂WO₄

Cu₂WO₄ was synthesized by comproportionation of elemental copper (metal powder, 5 μ m) and CuWO₄ under Argon. There are only a few studies on Cu₂WO₄ with the majority focusing on rapid high temperature flux syntheses facilitated by an electric arc or laser heating.^{3–5} To optimize the solid-state reaction route, experiments were performed with two different copper sources. The initial experiments were performed with $\sim 2-3$ mm squares of Cu⁰ foil (0.127 mm thick). However, the product was contaminated with unreacted residual foil following thermal treatments. Hence, the following studies were conducted with copper powder of 5 μ m size. CuWO₄ (3.2 mmol) and Cu⁰ powder (3.2 mmol) were ground for 30 min. to a uniform powder by mortar and pestle before the thermal treatment at 650 °C (30 min ramp, 8 h isothermal, ambient cooling) under an argon atmosphere (300 cc/min) in a one-zone tube furnace. A copper-foil cover was placed on top of the high alumina combustion boat to act as a sacrificial reductant for any trace O₂ contamination in the argon. Reacting the ground mixture of copper metal powder (5 μ m) and CuWO₄ at around the melting temperature of the product yielded phase pure maroon colored, rod-like Cu₂WO₄ crystals with preferred orientation as indicated by the preferential exposure of the (101) plane. (Fig. S2).



Fig. S2 XRD diagram of Cu_2WO_4 prepared by comproportionation of copper metal powder (5 µm) and $CuWO_4$ (standard pattern (ICDD PDF 00-041-0948) is also included for comparison)



Fig. S3 (a) CBTO powder collected by opening the copper box, inverting it, and tapping, (b) XRD patterns of the collected CBTO powder prepared by Cu_2WO_4 based route at 800 °C for 4 h in Cu rich atmosphere by different scientists six months apart



Fig. S4 Comparison of the XRD diagrams of CBTO prepared by annealing 4 times at 600 °C for 9 hours with intermittent ball milling after each annealing with a) Cu_2WO_4 or b) Cu_2O as ternary and binary precursors in Cu rich atmosphere (\star CBTO, \blacktriangle Bi₂WO₆, \blacktriangledown Bi₂W₂O₉, \bullet WO₃)



Fig. S5 SEM images of CBTO prepared by Cu_2WO_4 based route at 800 °C for 4 h in Cu rich atmosphere (a,b) as-synthesized and (c,d) after ball milling



Fig. S6 Atomic % data from various points on ball-milled CBTO obtained by SEM - energy dispersive X-ray spectroscopy (EDS)



Fig. S7 XRD diagrams of as-synthesized and ball-milled CBTO powders

2. Optical and Photocatalytic Properties of CBTO



Fig. S8 (a) UV-Vis spectrum of CBTO powder dispersed in water. (b) Valence and conduction band edges of $CBTO^6$ and $Bi_2WO_6^7$



Fig. S9 Cr(VI) photoreduction with CBTO under excitation with 100 mW/cm² light , 40 ml of 5 mg/L Cr(VI) solution, 10 mM CA, pH=2 unless stated otherwise (a) influence of citric acid concentration, (b) influence of the catalyst loading and spectral irradiance, (c) percentage adsorption of Cr(VI) by CBTO in the dark at RT with varying catalyst loading .

The highest photoreduction efficiency was obtained with 400 mg/L catalyst loading. The photoreduction reaction was ~ 1.8-fold faster under only visible light, most probably due to the higher energy intensity with short band pass filter (FES0750) in the region where CBTO absorption is stronger (Fig. S8). Dark adsorption of Cr(VI) increases with catalyst loading reaching closer to ~100% in the presence of 800 mg/L catalyst.



Fig. S10 (a) Spectrum of the 300 W Xe light source with a UV filter power adjusted to 100 mW/cm² and with a Thorlabs FES0750 filter powder adjusted to 90 mW/cm² as compared to ASTM G173-03 Reference Spectra Derived from SMARTS v. 2.9.2. (b) Transmission spectrum of a generic Thorlabs \emptyset 1" (\emptyset 25.4 mm) Shortpass Filter, Cut-On Wavelength: 750 nm (taken from the product website)

$CuBiW_2O_8 + hv \rightarrow CuBiW_2O_8(e^- + h^+)$	(S1)
$Cr_2O_7^2^- + 14H^+ + 6e^- \rightarrow 2Cr^{3+} + 7H_2O$	(S2)
$HCrO_{4}^{-} + 7H^{+} + 3e^{-} \rightarrow Cr^{3+} + 4H_{2}O$	(\$3)
$HCrO_{4}^{-} + 4H^{+} + 3e^{-} \rightarrow Cr(OH)_{3} + H_{2}O$	<i>(S4)</i>
$2HCrO_4^- + 8H^+ + 3e^- \rightarrow Cr_2O_3 + 5H_2O$	(\$5)
$Cr_2O_7^2^- + 8H^+ + 6e^- \rightarrow Cr_2O_3 + 4H_2O$	<i>(S6)</i>
$2H_2O + h^+ \rightarrow O_2 + 4H^+$	(S7)
$O_2 + e^- \rightarrow O_2^{\bullet-}$	(58)
$Cr(VI) + O_2^{\bullet^-} \rightarrow Cr(III) + O_2$	(S9)
$O_2^{\bullet -} + 2e^- + 2H^+ \rightarrow H_2O_2$	(S10)
$H_2O_2 \rightarrow 2 \ OH$	(S11)
$O_2^{\bullet-} + 2e^- + 2H^+ \rightleftharpoons 2 \bullet OH$	<i>(S12)</i>





Fig. S12 X-Ray Photoelectron (XPS) spectra of CBTO (800 C,4h, Cu-rich environment, ball milled for 12h) (a) as-synthesized, (b) unwashed powder after the photocatalytic test, (c) powder washed with water and ethanol after the photocatalytic test. Dotted traces correspond to the fitted peaks for Cu 2p, Bi 4f, W 4f, and C 1s regions. (Spectra taken from 3 different points with 10 scans at each point is shown for the C 1s region; following colors are used to denote point 1,2, and 3, respectively: pink, black, and blue.)

The surface composition of CBTO and the chemical bonding states of the metals before and after the photocatalytic reaction in acidic medium as well as the presence of adsorbed Cr species on CBTO surface were examined by studying the Cu 2p, Bi 4f, W 4f and Cr 2p core level XPS spectra.

XPS spectrum in the Cu 2p region of the ball milled CBTO display three peaks at 932.4, 934.6, and 936.6 eV with strong shake-up peaks in the 940-945 eV region. The peaks around 932-934 eV are commonly observed for Cu²⁺ and those around 931-932 eV are attributed to Cu¹⁺ in literature.^{8,9} In addition, the high intensity satellite peak located around 9 eV higher binding energy than Cu 2p_{3/2} peak is typically observed in Cu²⁺ oxides.^{10–12} Since Cu¹⁺ and Cu peaks in the 2p region are very close to each other, generally X-Ray

induced Cu LMM Auger lines around 570 eV are taken into consideration in distinguishing between these two states. The Cu $L_3M_{45}M_{45}$ line at 570.2 eV in Fig. S12a is a clear indication of Cu¹⁺ species.^{9,13,14} Hence, we ascribe the fitted peak at 932.4 to Cu¹⁺ in CBTO and the peaks at 934.6, and 936.6 eV to Cu²⁺ oxide related impurities on CBTO surface, in line with our previous report.⁶ It can be seen in Fig. S12a that three peaks appear in the Bi 4f_{7/2} (158.8, 159.2, 161.3 eV) and Bi 4f_{5/2} (164.1, 164.8, 166.7 eV) regions for CBTO before the reaction. It is known from the XRD patterns of CBTO (Fig. 2) that Bi₂WO₆ and Bi₂W₂O₉ impurities are present. Hence, these three sets of peaks can be ascribed to Bi³⁺ in different local chemical environments, likely generated by CBTO, Bi₂WO₆ and Bi₂W₂O₉.¹⁵⁻¹⁷ Similarly, three sets of peaks appearing in the W 4f_{7/2} (34.9, 35.8, 37.1 eV) and W 4f_{5/2} (37.2, 37.7, 39.9 eV) regions can be attributed to W⁶⁺ likely generated by CBTO, Bi₂WO₆ and Bi₂W₂O₉.¹⁸⁻²¹

After the photocatalytic reaction, XPS features in Cu 2p, Bi 4f, and W 4f and regions due to the surface impurities disappear (Fig. S12b-c) indicating low stability of these materials under irradiation and/or in the acidic aqueous medium in line with previous reports. Early studies on photocatalytic stability of Bi_2WO_6 in acidic solutions (pH < 5) showed that Bi_2WO_6 is transformed into H_2WO_4 and Bi_2O_3 under visible light irradiation.²² $Bi_2W_2O_9$ which is a layered material where perovskite like $[W_2O_7]^2$ -slabs are separated by $[Bi_2O_2]^{2+}$ groups, is found to be susceptible to selective leaching in acidic environment giving rise to formation of layered tungstic compounds.^{23–25} CuO is also reported to be unstable in acidic solutions.^{26,27} At low pH, CuO is dissolved with significant Cu²⁺ leaching. Natural organic matter such as humic acid and citric acid also shown to improve dissolution of CuO particles.²⁸

Moreover, no peak associated to Cr species appears to be present after the photocatalytic reaction (Fig. S12b-c). Cr 2p doublets due to Cr(VI) and Cr(III) features usually appear at binding energies of 579-589 eV and 577-586 eV, respectively.^{29,30} In Fig S12b, no peaks appear in this region. The peak at around 570 eV present in Fig. S12c is due to the Cu $L_3M_{45}M_{45}$ Auger line as discussed above.

The change in the C 1s region spectra is also given in Fig.S12. 10-scan averages at 3 different physical locations were collected. For the unreacted CBTO, characteristic peaks of adventitious carbon contamination are seen at 284.8 eV (C-C) and 288.4 eV (C=O or C-O-C).³¹ After the photocatalytic reaction, additional features appear at 286-287 eV and 290 eV (Fig. S12-13) which can be attributed to C-OH and carboxylic groups and in line with reported citric acid XPS data.³² At point location 3, an additional strong peak at 292.9 eV appears which can be associated with alkali carboxylates³³ or K 2p_{3/2} peak in potassium carbonate/carboxylates.^{34,35} This study does not exclude the possibility of reduced forms of citric acid being present on the surface of the catalyst.³² A more detailed, time-dependent analysis is needed to monitor the relative intensity changes in the peaks associated with C-C,C=C,C-O-C, C-OH, C=O, and O-C-OH groups complemented with optical spectroscopy measurements.



Figure S.13 C 1s region of unwashed CBTO after the reaction a) spectrum collected from point 3 and the fitted peaks (on the left), b) table displaying the binding energies of the fitted peaks in all 3 points



Figure S.14 Cr(VI) photoreduction with CBTO under excitation with 100 mW/cm² light , 40 ml of 5 mg/L Cr(VI) solution, 10 mM CA, pH=2, 200 mg/L CBTO.

3. Estimation of number of Cr(VI) ions to CBTO surface atom ratio

We have estimated the ratio of number of Cr(VI) ions to the number of CBTO surface atoms, for each photocatalytic test. The amount of Cr(VI) added in each photocatalytic test (5 mg/L in 40 mL volume) is a total of 2.3×10^{18} ions. As described in the manuscript, the CBTO particle size ranges from ~ 15 µm to 100 nm. Furthermore, the particles have smooth surfaces and are not porous. To find an upper limit for the number of CBTO surface atoms, we can assume that all the CBTO particles have the smallest diameter of 100 nm. The total number of surface atoms of CBTO (for 200 mg/L of CBTO in 40 mL volume) is then calculated to be 2.0×10^{17} atoms based on the primitive crystallographic unit cell volume of 157.4 Å³. Therefore, the number of Cr(VI) ions that are photoreduced in each test is at least 10 times larger than the total number of CBTO surface atoms. Therefore, each active site on the CBTO photocatalyst surface is used many times during each photocatalytic Cr(VI) photoreduction test, suggesting that the CBTO photocatalyst is reusable. If a more realistic value of 1 µm is used for average CBTO particle diameter, the total number of surface atoms of CBTO is 2.0×10^{16} atoms, and the number of Cr(VI) ions is 100 times larger than the total number of surface atoms of CBTO is 2.0×10^{16} atoms, and the number of Cr(VI) ions is 100 times larger than the total number of surface atoms of CBTO is 2.0 × 10^{16} atoms, and the number of Cr(VI) ions is 100 times larger than the total number of surface atoms of CBTO is 2.0 × 10^{16} atoms, and the number of Cr(VI) ions is 100 times larger than the total number of surface atoms of CBTO is 2.0 × 10^{16} atoms, and the number of Cr(VI) ions is 100 times larger than the total number of surface atoms of CBTO for each photoreduction test.

Table S1 Photocatalytic Cr(VI) reduction activity of CBTO as compared to the photocatalysts reported in recent literature

Catalyst	Catalyst	Initial	PRP	Time	Light Source	рН	Additives	Ref
	Loading	[Cr(VI)]						
	(mg/L)	(mg/L)						
CuBiW ₂ O ₈	200			20 min	100 mW/cm ²		10 mM	Thic
		5	~100 %		(300 W Xe lamp	2	Citric	
	400			15 min	with UV filter)		acid	work
Bi ₂ O ₃ / CuBi ₂ O ₄ /Ag NP	400	10	96.9 %	30 min	Visible Light	2	8 mM	36
					(250 W)		Citric	
							acid	
CuFeO ₂	400	5	97	60 min	500 W Xe	3	80 mM	37
							Formic	
							acid	
Bi ₂ WO ₆ porous nanosheets	1200	10	99.5 %	100	300 W Xe	-	480 mM	38
				min	Visible light		Oxalic	
							acid	
Cu ₂ O / BiVO ₄	500	0.08	100 %	120	300 W Xe	-	-	39
		mM		min	Visible light			
BiFe ₄ O ₉	750	25	100 %	180	200 W Tungsten	2	-	40
				min				
Au NP/ g-C ₃ N ₄ nanosheet	1000	20	87%	30 min	300 W Xe	-	6.9 mM	41
/W ₁₈ O ₄₉					AM 1.5		Oxalic	
					visible light		acid	

4. References

- 1 Z. Wu, Z. Zhao, G. Cheung, R. M. Doughty, A. R. Ballestas-Barrientos, B. Hirmez, R. Han, T. Maschmeyer and F. E. Osterloh, *J Electrochem Soc*, 2019, **166**, H3014–H3019.
- 2 P. Yadav and E. Sinha, *Macromol Symp*, 2019, **388**, 1900019.
- 3 H. Mumm and H. MiiLLER-BUSCHBAUM Kiel, *Journal of the Less-Common Metals*, 1988, **142**, 85–90.
- 4 B. O. Marinder, P. L. Wang, P. E. Werner, M. Westdahl, A. F. Andersen and D. Louer, *Acta Chem. Scand.*, 1987, **A 41**, 152–157.
- M. Tayar Galante, A. Živković, J. C. Alvim, C. C. Calchi Kleiner, M. Sangali, S. F. R. Taylor, A. J.
 Greer, C. Hardacre, K. Rajeshwar, R. Caram, R. Bertazzoli, R. T. Macaluso, N. H. de Leeuw and C.
 Longo, ACS Appl Mater Interfaces, 2021, 13, 32865–32875.
- L. Zhou, E. Bainglass, M. Masroor, B. Giri, G. Li, A. Carl, R. L. Grimm, M. N. Huda, L. v. Titova and P.
 M. Rao, J Mater Chem A Mater, 2021, 9, 1643–1654.
- 7 B. Huang and J. N. Hart, *Physical Chemistry Chemical Physics*, 2020, **22**, 1727–1737.
- J. Haber, T. Machej, L. Ungier and J. Zidekowski, *J Solid State Chem*, 1978, **25**, 207–218.

- 9 T. H. Fleisch and G. J. Mains, *Application of Surface Science*, 1982, **10**, 51–62.
- 10 S. Poulston, P. M. Parlett, P. Stone and M. Bowker, *Surface and Interface Analysis*, 1996, **24**, 811–820.
- 11 G. Morettit, G. Fierro, M. lo Jacono and P. Porta, *Surface and Interface Analysis*, 1989, **14**, 325–336.
- 12 J. Ghijsen, L. H. Tjeng, J. van Elp, H. Eskes, J. Westerink, G. A. Sawatzky and M. T. Czyzyk, *Phys Rev B*, 1988, **38**, 11322–11330.
- 13 Y. S. Lee, K. Y. Lim, D. Y. Chung and C. N. Whang, *Journal of Surface Analysis*, 1999, **5**, 204–207.
- 14 X. Zhang, M. Xia, F. Wang and W. Lei, *Ionics (Kiel)*, 2020, **26**, 6359–6369.
- F. Wang, X. Zhou, J. Li, Q. He, L. Zheng, Q. Liu, Y. Chen, G. Zhang, X. Liu and H. Li, *Molecules*, 2021, 26, 7334.
- 16 S. Kang, R. C. Pawar, Y. Pyo, V. Khare and C. S. Lee, *J Exp Nanosci*, 2016, **11**, 259–275.
- D. Lahiri, S. Chattopadhyay, J. Kaduk, al -, H. Zhang, W. Zhao, H. Shi -, Y.-P. Wang, S.-S. Li and W. X. Ji, *Jpn J Appl Phys*, 1992, **31**, L953–L955.
- 18 S. Rahimnejad, J. H. He, F. Pan, X. Lee, W. Chen, K. Wu and G. Q. Xu, *Mater Res Express*, 2014, **1**, 045044.
- 19 M. E. Pam, Y. Shi, J. Hu, X. Zhao, J. Dan, X. Gong, S. Huang, D. Geng, S. Pennycook, L. K. Ang and H. Y. Yang, *Nanoscale Adv*, 2019, **1**, 953–960.
- 20 B. V. R. Chowdari, K. L. Tan and W. T. Chia, *Solid State Ion*, 1992, 1172–1178.
- 21 G. E. McGUIRE, G. K. Schweitzer and and A. Thomas Carlson, *Inorg Chem*, 1973, **12**, 2450.
- 22 H. Fu, C. Pan, W. Yao and Y. Zhu, *Journal of Physical Chemistry B*, 2005, **109**, 22432–22439.
- 23 R. Wang, Y. Sun, A. Brady, S. Fleischmann, T. B. Eldred, W. Gao, H. W. Wang, D. en Jiang and V. Augustyn, *Adv Energy Mater*, 2021, **11**, 2003335.
- R. E. Schaak and T. E. Mallouk, *Chemical Communications*, 2002, **2**, 706–707.
- 25 M. Kudo, H. Ohkawa, W. Sugimoto, N. Kumada, Z. Liu, O. Terasaki and Y. Sugahara, *Inorg Chem*, 2003, **42**, 4479–4484.
- N. Habbache, N. Alane, S. Djerad and L. Tifouti, *Chemical Engineering Journal*, 2009, 152, 503–508.
- 27 S. Xing, W. Li, B. Liu, Y. Wu and Y. Gao, *Chemical Engineering Journal*, 2020, **382**, 112837.
- 28 C. Peng, C. Shen, S. Zheng, W. Yang, H. Hu, J. Liu and J. Shi, *Nanomaterials*, 2017, **7**, 326.
- 29 S. Pu, Y. Hou, H. Chen, D. Deng, Z. Yang, S. Xue, R. Zhu, Z. Diao and W. Chu, *Catalysts*, , DOI:10.3390/catal8060251.

- 30 S. H. Zhang, M. F. Wu, T. T. Tang, Q. J. Xing, C. Q. Peng, F. Li, H. Liu, X. B. Luo, J. P. Zou, X. B. Min and J. M. Luo, *Chemical Engineering Journal*, 2018, **335**, 945–953.
- V. Fernandez, N. Fairley and J. Baltrusaitis, *Appl Surf Sci*, , DOI:10.1016/j.apsusc.2020.148031.
- R. Ludmerczki, S. Mura, C. M. Carbonaro, I. M. Mandity, M. Carraro, N. Senes, S. Garroni, G.
 Granozzi, L. Calvillo, S. Marras, L. Malfatti and P. Innocenzi, *Chemistry A European Journal*, 2019, 25, 11963–11974.
- 33 S. Oswald, F. Thoss, M. Zier, M. Hoffmann, T. Jaumann, M. Herklotz, K. Nikolowski, F. Scheiba, M. Kohl, L. Giebeler, D. Mikhailova and H. Ehrenberg, *Batteries*, DOI:10.3390/batteries4030036.
- A. v Shchukarev and D. v Korolkov, *Central European Science Journals*, 2004, **2**, 347–362.
- 35 S. Yokoyama, K. Tanaka, I. Toyoshima, K. Miyahara, K. Yoshida and J. Tahshiro, *Chemical Society of Japan*, 1980, 599–602.
- 36 D. Majhi, A. Kumar Mishra, K. Das, R. Bariki and B. G. Mishra, *Chemical Engineering Journal*, 2021, **413**, 1227506.
- 37 Q. Xu, R. Li, C. Wang and D. Yuan, *J Alloys Compd*, 2017, **723**, 441–447.
- 38 F. Xu, H. Chen, C. Xu, D. Wu, Z. Gao, Q. Zhang and K. Jiang, *J Colloid Interface Sci*, 2018, **525**, 97–106.
- 39 Q. Yuan, L. Chen, M. Xiong, J. He, S. L. Luo, C. T. Au and S. F. Yin, *Chemical Engineering Journal*, 2014, **255**, 394–402.
- 40 M. Kebir, A. Boudjemaa, Y. Azoudj, M. Sehailia and K. Bachari, *Canadian Journal of Chemical Engineering*, 2018, **96**, 2292–2298.
- 41 L. Shi, Z. Li, K. Marcus, G. Wang, K. Liang, W. Niu and Y. Yang, *Chemical Communications*, 2018, **54**, 3747–3750.